For Microscopists by Microscopists

Microscopy TODAY

2021 BUYERS' GUIDE

Rates and Instructions • Deadline: December 11, 2020

On the following pages please find Information on the listings available for purchase in Microscopy Today 2021 Buyers' Guide and the Insertion Order forms. There are separate files with Word templates of the different types of listings.

Please fill out electronically and send to:

Kelly Miller • Email: kmiller@mrvica.com • Phone: 856.768.9360

IMPORTANT:
Scanned PDFs and handwritten forms will not be accepted.
Please contact Kelly Miller with any questions or concerns.

Ad materials should be submitted directly to Kelly Miller at **kmiller@mrvica.com**.

Specifications for Company Profiles, Images, and Major Listings

Recommended submission format: High-res PDFs with embedded fonts, plus supporting files and fonts. Windows format PSD, TIF or EPS files accepted; MAC format accepted. Images saved with OPI cannot be accepted. CMYK only, NOT RGB. Flattened PDFs will not be accepted. Images should be minimum 600 dpi.

MSA
Microscopy Society of America

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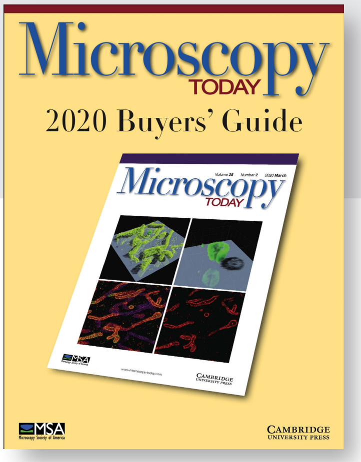
Microscopy TODAY 2021 BUYERS' GUIDE



Types of listings:

Rates:

Type	Example	Description	Rate
Company Profile	Applied Beams LLC Company Profile Phone number Company URL	Full page profile (see sample at right) plus benefits of one major listing	**Company profile: $1,655**
Major Listing	DEBEN Phone number Company URL	Listed in Company Index, major listing entry in "Microscopy Product Vendors" with logo and photo plus catalog URL (linked in digital edition)	**Major Listing: $770, additional product: $220**
Minor Listing	My Company Instruments Company URL	Company URL in Product and Services Index under five keywords	**Minor listing: $25**

PRODUCT AND SERVICES INDEX - sample

Accessories (miscellaneous)
Chroma Technology Corp.
800-824-7662
www.chroma.com
Microscopy Innovation, LLC
888-302-3925
www.microscopyinnovations.con
Protochips, Inc.
919-341-2612
www.protochips.com
QImaging
604-530-5800
www.Qimaging.com
Ted Pella, Inc.
800-237-3526
www.tedpella.com
TEMWindows.com (SimPore, Inc.)
888-323-6266
www.temwindows.com

AFM/SPM Accessories
Ted Pella, Inc.
800-237-3526
www.tedpella.com

Nanolane
33-2-43-54-09-00
www.nano-lane.com
Nanonics Imaging, Ltd.
1-866-220-6828
www.nanonics.co.il
Nanoscience Instruments
480-940-3940
www.nanoscience.com
Nea Spec GmbH
49-176-2320-3996
www.neaspec.com
Park Systems, Inc.
408-986-1110
www.parkAFM.com
Quantom Design, Inc.
858-481-4400
www.qdusa.com
WITec Instruments Corp.
865-984-4445
www.witec.de

Auger Microscopes
JEOL USA, Inc.
978-535-5900

Company Profile

Applied Beams LLC

APPLIED BEAMS

Applied Beams LLC is a leading supplier of FIB and SEM consumables, custom-configured systems, and micro-machining services, and we bring new life to your SEM and FIB system with our upgrades that extend and enhance system performance. With 30+ years of experience with ion and electron beam systems design, manufacture and applications we provide a unique ability to meet customer needs with these powerful technologies.

We serve the semiconductor, materials analysis and research communities, and proudly support the US Government with our unique ability to develop and deliver custom FIB and SEM systems.

- **HyperFIB upgrade**—Our high-current HyperFIB system is the only plasma FIB upgrade on the market for legacy FIB tools, increasing available current for micromachining, cross-sectioning and material deposition from just 20nA to over 7uA, an improvement of 350X!
- **Consumables**—Our high quality, affordable consumables are direct replacements for original components, keeping your FIB, SEM and dual column FIB-SEM systems operating at optimum performance and on budget.
- **Scanning electron microscopes**—We've brought the CamScan Electron Optics electron microscopes back to market and offer customized versions of the popular CS-series of SEMs. Derived from CamScan Helios™ software, our Caesium™ control system provides new features including up to 20 images displayed per Window, drag and drop image open and save, and support for advanced techniques such as our Quantitative EBIC Measurement System. Caesium also brings your SEM into the 21st century with a client-server architecture on the Microsoft Windows 7 operating system.
- **analytical services**—Our micromachining services erFIB systems. With up to 7uA of beam current this tool cross-sections of advanced semiconductor devices and ion of a semiconductor device.

customers include Fortune 500 companies, top research ent laboratories.

How to find us

Applied Beams LLC
14855 SW Murray Scholls Drive
Beaverton, OR 97007
Tel: +1 (503) 608-7237
Fax: +1 (503) 214-8057
Email: info@appliedbeams.com
www.appliedbeams.com

www.cambridge.org/mto 3

Company Profile

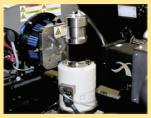
sample

Major Listing

sample

Deben
Tel: +44 (0) 1359 244 870; +1 201 410 5028
Email: paulg@deben.co.uk
www.deben.co.uk

In-Situ Testing for Microscopy



APPLICATIONS: • micro CT tensile scanning stages • Centaurus scintillator CL and back scattered electron (BSE) detectors • STEM detectors for SEM • SEM heating and cooling Peltier stages • Microtest tensile and compression stages

FEATURES: Deben manufacture in-situ testing stages as well as innovative accessories for SEM and TEM including SEM detectors, stages, stage automation and Peltier heating & cooling stages

http://deben.co.uk/products/

Minor Listing

FREE listings in up to 5 indexing categories. Additional listings available: $25 each

My Company Instruments	www.mci.com

Closing Date: December 11, 2020

If an advertiser fails to provide new artwork for a particular issue by the materials closing date deadline (or a pre-approved extension granted by the Publisher), then the Publisher will pick up the most recent artwork provided. If no artwork is on hand, then the advertiser will still be responsible for payment on the space.

Cancellations are not accepted after the closing date.

Free listings will be automatically renewed each year unless written notification of changes or cancellation is submitted by advertiser.

HOW TO RESERVE YOUR LISTING

Contact Kelly Miller at 856.768.9360;
Email: kmiller@mrvica.com for details.

Product Category Keywords

(Please choose the category which best describes your product.)

3D Diffraction Tomography
3D Live Cell Imaging
3D Tomography Software
6-Axis Positioners
Accessories (miscellaneous)
Acoustic Enclosures for SEMs
Acoustic Microscopes
AFM Probes
AFM/SPM Accessories
Amplitude Modulation Microscopy
Analytical Balance
Antibodies
Anti-Contamination Systems
Anti-Vibration Devices
Apertures
Atom Probe
Atomic Force Microscopes (AFMs)
Auger Microscopes
Autofocus Systems
Automation/Robotic Equipment
Backscattered Electron Detectors
Beam Splitters
Benchtop SEM
Biology and Cytology
Bioreactor Cell Culture System
Books and Textbooks
Calibration and Reference Standards
Camera/Digital Camera Systems
Cameras, EMCCD
Cameras, Intensified CCD
Cameras, CMOS
Cantilevers
Carbon Coaters
Carbon Nanotube Probes for AFM
Cameras, CCD
Centrifuges
Chemicals
Clean Room Accessories
Cleaving
Coating Supplies
Coating Systems
Coating Thickness Gauge
Cold Sputtering Equipment
Colloidal Gold
Confocal Microscopes
Consulting
Contract Research
Cooling Systems
Correlative Microscopy
Courses/Workshops
Critical Point Dryers
Cryoequipment
Cryostats
Cryotransfer Equipment (EM)
Cryo-Ultramicrotome
Crystallographic Mapping
Cut-Off Machines
Databases
Desiccators
Detectors
Diamond Knives
Diamond Scribing Tools
Diamond Wire Saws
Differential Interference Contrast
Diffraction Calibration
Digital Archiving/Data Storage
Digital Light Microscopes
Dry Milling
Dual Beam FIB/SEM
E Beam Lithography
EBSD Courses
EDS Courses
EDS Detector Repairs and Upgrades
EDS Detectors & Systems
Education
Electrical Characterization
Electron Backscatter Diffraction (EBSD)
Electron Crystallography
Electron Energy Loss Spectrometry (EELS)
Electron Guns
Electron Microprobes/EPMA
Electron Microprobe Automation Systems
Electron Microprobe Courses
Electron Microprobe Service
Electron Probe Microanalyzers (EPMAs)
Electrostatic Force Microscope
Embedding Materials
EMI Cancellation
Energy-Dispersive X-ray Spectrometry (EDS)
Energy Filters (EM)
Environmental Chambers
Environmental TEM
Evaporation Sources
Evaporation Systems
Facility Management System
Failure Analysis
FIB Accessories
FIB Lift-out
FIB-SEMs
FIB Service Laboratories
Field Emission Sources (See Filaments)
Filaments and Filament Rebuilding
Filters (See Optical Filters)
Fixatives and Chemicals
Fluorescence-Lifetime Imaging Microscopy (FLIM)
Fluorescence Microscopy
Fluorescence Resonance Energy Transfer (FRET)
Fluorophores
Focused Ion Beam Courses (FIB)
Focused Ion Beam Systems/Workstations
Forensic Testing Supplies
Freeze Drying Equipment
FT-IR Microscopy
Furnaces
Gas Injection Systems
Gauges (Vacuum)
Glass Knives
Gloves
Gold Nanoparticles/Probes
Grids (EM)
Hand Loupes
Heat Exchangers
Heating Stages
Helium & Ion Microscopes

Product Category Keywords
Continued

(Please choose the category which best describes your product.)

High Definition Cameras
High Speed Imaging
Histology Supplies
Hoffmann Modulation Microscopy
Holographic Microscopes
Hot Plates
Illuminators, Light Microscopy
Image Analysis and Processing
Image Analysis Software
Impedance Spectroscopy
Immunolabeling
Incubators for Live Cell Imaging
Indenters
Infra-Red Microscopes
In-Situ SEM
In-Situ TEM
Integrated EDS, EBSD, WDS Microanalysis
Inverted Light Microscopes
Ion Beam Milling
Ion Beam Polishers
Ion Guns
Ion Microscopes
Ion Pumps, New and Rebuilding
Journals
Knifemakers
Knife Resharpening
Knives
Laboratory Fume Hoods
Laboratory Furniture
Laboratory Information Management System (LIMS)
Laboratory Safety Supplies
Laminar Flow Hoods
Lamps and Light Sources
Large Area AFM
Laser Capture Microscopy
Lasers
Laser Scanning Confocal Microscopes
Leak Detectors
LED Illumination
Lenses
Light Microscopes (LOMs)
Light Tight Imaging Chamber
Lightsheet
Live-Cell Chambers
Live-Cell Imaging
Magnetic Field Cancellation
Magnification Calibration
Mass Spectrometers/Residual Gas Analyzers
Materials Characterization
Materials Science
Measuring Microscopes
Mechanical Microprobes
Megapixel Cameras (See Cameras/ Digital Camera Systems)
Mercury Lamps
Metallographic Equipment
Metallographic Microscopes
Metrology Instruments
Micro Balance
Micro-CT Scanning
Micro Milling Machine
Micro Tools
Micro X-ray Fluorescence
Microanalysis Services
Microelectromechanical Systems (MEMS)
Microinjectors
Micromanipulators
Microscope Enclosures
Microscope Immersion Oil
Microscope Slides
Microscope Stages
Microscope Stands
Microscope Viewing Heads
Microscopy Applications
Microscopy Education
Microscopy Services
Microtomes and Ultramicrotomes
Microtome Repair
Microwave Tissue Processing
Moisture Balance
Monoclonals
Multiphoton Microscopes
Multiprobe Imaging
Nano Indentation
Nanomanipulators
Nanopositioners & Stages
Nanopositioning Motors
Nanoprobes
Nanoprobes/Mechanical Microprobes
Nanosensors
Nanotools
Near-Field Scanning Optical Microscopes (NSOMs)
New and Used Equipment
NIR Composition Analyzers
NIR Moisture Meter
Normarski Interference Contrast
Objective Lenses
Ocular Lenses
Optical Filters
Optical Prototyping System
Orientation and Phase Analysis, TEM
Osmium Coaters
Particle Analyzer
Particle Characterization Services
Perfusion System
Phase Contrast Microscopy
Phase Identification
Photoactivated Localization Microscopy (PALM)
Photography Supplies
Photometers
Piezo Stages and Controllers
Plasma Cleaners
Polarized Light Microscopy
Polarizers
Polishing Consumables
Polishing Equipment
Positioning Systems
Powder Blenders
Precession Electron Diffraction
Precision Positioning Stages
Prepared Slides
Prisms (See Beam Splitters)
Proportional Counter Windows
Publishers
Quartz Slides
R&D Pilot Production Systems
R&D Sputter Systems
Raman Optical Filters
Raman Spectroscopy/Microscopy
Recirculating Water Chillers
Reference Materials/Reference Standards (See Calibration and Reference Standards)
Reflection Light Microscope
Refractive Index Liquids
Resharpening Services (See Knife Resharpening)
Resolution Standards
Sample Preparation & Handling
Sample Storage

(Please choose the category which best describes your product.)

Scan Interface for SEM and STEM
Scanners (SPM)
Scanning Electron Microscopes (SEMs)
Scanning Electron Microscopy Courses (SEM)
Scanning Probe Microscopes (SPMs)
Scanning Transmission Electron Microscopes (STEMs)
Scanning Transmission Electron Microscopy (STEM) Courses
Scanning Tunneling Microscopes
Scintillators
Screen Recoating
Secondary Ion Mass Spectrometer (SIMS)
Section Stainers
SEM Accessories
SEM Analysis Services
SEM/STEM Digital Imaging Systems
SEM and TEM Sample Holders
Semiconductor Failure Analysis
Service and Repair
Service Laboratories
Short Courses
Silicon Drift Detectors (SDD) for SEM and TEM
Slides and Coverslips
Small Tools
Society and Event Organizer
Software for Microscopy
Software for Microanalysis
Spatial Light Modulator
Specimen Holders
Specimen Preparation Equipment
Specimen Preparation & Handling
Specimen Preparation Supplies
Specimen Stages
Spectrometers (light)
Spectrometers (X-ray)
Spinning Disk Confocal Microscopy
Spinning Disk Microscopy
SPM Signal Analyzer/Controller
SQUID
Stage Automation
Stage Micrometers
Stains
Standards for Microanalysis
Stepper Motor Based Linear Actuators
Stereo 3D Imaging and Measurement
Stereo & Zoom Microscopes
Stereoscopic Viewing Systems
Stimulated Emission Depletion Microscopy (STED)
Stochastic Optical Reconstruction Microscopy (STORM)
Storage supplies
Structured Illumination Microscopy (SIM)
Student Microscopes
Super Resolution Microscopy
Supplies
Surface Analysis
Surface Profiling
Take-off Angle Imaging
Tabletop SEM
TEM Accessories
TEM Grids
TEM Imaging Software
TEM Sample Handling
TEM and SEM Specimen Preparation
Testing Equipment
Thin Film Thickness Measurement
Thin-walled Capillary Tubes
Tip Calibrators
Tips (SPM)
Tissue Processors
Tools
Total Internal Reflection Microscopy (TIRF)
Trace Element Analysis Services
Transmission Electron Microscopes (TEMs)
Tweezers
Ultramicrotomes (See Microtomes & Ultramicrotomes)
Ultrasonic Cleaners
Ultrasonic Tweezers
Used Equipment
Vacuum Equipment
Vacuum Evaporators
Vacuum Oils
Vacuum Tweezers
Vibration Isolation Systems
Vibratomes
Vibratory Slicers
Video Microscopes
Water Chillers
Wavelength Dispersive X-ray Spectrometry (WDS)
WDS Detectors & Systems
Wet Milling
Wide Field Microscopes
Xenon Focused Ion Beam
Xenon Lamps
X-ray Analysis Equipment
X-ray Microscopy
X-ray Photoelectron Spectrometers/Microscopes
X-ray Windows
Zeta Potential Analyzer

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